







SN74AHCT14Q-Q1

SGDS023D - FEBRUARY 2002 - REVISED OCTOBER 2023

SN74AHCT14Q-Q1 Automotive Hex Schmitt-Trigger Inverter

1 Features

- Qualified for automotive applications
- EPIC™ (Enhanced-Performance Implanted CMOS) process
- Inputs are TTL-Voltage compatible
- Latch-Up performance exceeds 250 mA per JESD

2 Applications

- Synchronize invterted clock inputs
- Debounce a switch
- Invert a digital signal

3 Description

The SN74AHCT14Q-Q1 contains six independent inverters. This device performs the Boolean function $Y = \overline{A}$

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE(2)	BODY SIZE (NOM)(3)					
	D (SOIC, 14)	8.65 mm × 6 mm	8.65 mm × 3.9 mm					
SN74AHCT14Q-Q1	PW (TSSOP, 14)	5 mm × 6.4 mm	5 mm × 4.4 mm					
	BQA (WQFN, 14)	3 mm × 2.5 mm	3 mm × 2.5 mm					

- For all available packages, see the orderable addendum at the end of the data sheet.
- The package size (length × width) is a nominal value and includes pins, where applicable
- The body size (length × width) is a nominal value and does not include pins.



Logic Diagram, Each Inverter (Positive Logic)



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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision C (June 2023) to Revision D (Octob	er 2023)
• Updated RθJA values: PW = 113 to 147.7, all values in °C/W	
Added Application and Implementation section	
Changes from Revision B (May 2023) to Revision C (June 20	D23) Pag
Added the Applications section	
• Updated the Package Information table to include package le	eads and body size
Added the BQA package	

Product Folder Links: SN74AHCT14Q-Q1



5 Pin Configuration and Functions

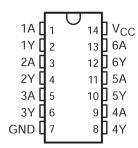


Figure 5-1. D or PW Package, 14-Pin SOIC or TSSOP (Top View)

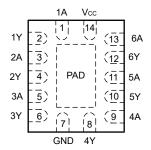


Figure 5-2. BQA Package, 14-Pin WQFN (Top View)

	PIN	TVDE4	DEGODIDATION
NAME	NO.	TYPE1	DESCRIPTION
1A	1	I	Input 1A
1Y	2	0	Output 1Y
2A	3	1	Input 2A
2Y	4	0	Output 2Y
3A	5	1	Input 3A
3Y	6	0	Output 3Y
4Y	8	0	Output 4Y
4A	9	1	Input 4A
5Y	10	0	Output 5Y
5A	11	1	Input 5A
6Y	12	0	Output 6Y
6A	13	1	Input 6A
GND	7	_	Ground Pin
NC	_	_	No Connection
V _{CC}	14	_	Power Pin
Thermal Pad ¹		_	The thermal pad can be connected to GND or left floating. Do not connect to any other signal or supply.

(1) For BQA package only.



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	7	V
V _I ¹	Input voltage range		-0.5	7	V
V _O ¹	Output voltage range		-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	(V _I < 0)		-20	mA
I _{OK}	Output clamp current	$(V_O < 0 \text{ or } V_O > V_{CC})$		±20	mA
I _O	Continuous output current	$(V_O = 0 \text{ to } V_{CC})$		±25	mA
	Continuous current through V _{CC} or GND			±50	mA
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human body model (HBM), per AEC Q100-002 ⁽¹⁾	±2000	\/
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per AEC Q100-011	±200	·

⁽¹⁾ AEC Q100-002 indicates that HBM stressing must be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

6.3 Recommended Operating Conditions

(over recommended operating free-air temperature range (unless otherwise noted)¹

		MIN	MAX	UNIT
V _{CC}	Supply voltage	4.5	5.5	V
VI	Input voltage	0	5.5	V
Vo	Output voltage	0	V _{CC}	V
I _{OH}	High-level output current		-8	mA
I _{OL}	Low-level output current		8	mA
T _A	Operating free-air temperature	-40	125	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

6.4 Thermal Information

		S	N74AHCT14Q-C) 1	
	THERMAL METRIC(1)	THERMAL METRIC ⁽¹⁾ D PW BQA			
$R_{\theta JA}$	Junction-to-ambient thermal resistance	86	147.7	88.3	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report (SPRA953).

Product Folder Links: SN74AHCT14Q-Q1

⁽²⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		T _A = 25°C			MINI		LINUT	
PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	MIN	MAX	UNIT	
V _{T+} Positive-going		4.5 V	0.9		1.9	0.9	1.9	V	
input threshold voltage		5.5 V	1		2.1	1	2.1	V	
V _{T-} Negative-going		4.5 V	0.5		1.5	0.5	1.5	V	
input threshold voltage		5.5 V	0.6	-	1.7	0.6	1.7	V	
ΔV _T Hysteresis (V _{T+} -		4.5 V	0.4		1.4	0.4	1.4	V	
V _{T-})		5.5 V	0.4		1.5	0.4	1.5	V	
V	I _{OH} = -50 μA	4.5 V	4.4	4.5		4.4		V	
V _{OH}	I _{OH} = -8 mA	4.5 V	3.94			3.8		V	
V	I _{OL} = 50 μA	4.5 V		-	0.1		0.1		
V _{OL}	I _{OL} = 8 mA	4.5 V			0.36		0.44	V	
I _I	V _I = 5.5 V or GND	0 V to 5.5 V			±0.1		±1	μΑ	
I _{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			2		20	μA	
ΔI _{CC} (1)	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35		1.5	mA	
C _i	V _I = V _{CC} or GND	5 V		2	10			pF	

⁽¹⁾ This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

6.6 Switching Characteristics

over recommended operating free-air temperature range V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Load Circuit and Voltage Waveforms)

PARAMETER	FROM	TO (OUTBUT)	LOAD CAPACITANCE	T _A :			MIN	MAX	UNIT	
PARAMETER	(INPUT)	10 (001701)	LUAD CAPACITANCE	MIN	TYP	MAX		WAA	ONT	
t _{PLH}	^	Y	C _L = 15 pF		4	7	1	8	ns	
t _{PHL}	Α				4	7	1	8		
t _{PLH}	^	V	0 - 50 - 5		5.5	8	1	9	no	
t _{PHL}	A	^ f	ľ	$C_L = 50 \text{ pF}$		5.5	8	1	9	ns

6.7 Noise Characteristics

 $V_{CC} = 5 \text{ V}, C_L = 50 \text{ pF}, T_A = 25^{\circ}\text{C}^{(1)}$

	PARAMETER	MIN	TYP	MAX	UNIT
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.9		V
$V_{OL(V)}$	Quiet output, minimum dynamic V _{OL}		-0.7		V
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}		4.3		V
V _{IH(D)}	High-level dynamic input voltage	2.1			V
$V_{IL(D)}$	Low-level dynamic input voltage			0.5	V

⁽¹⁾ Characteristics are for surface-mount packages only.

6.8 Operating Characteristics

 $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$

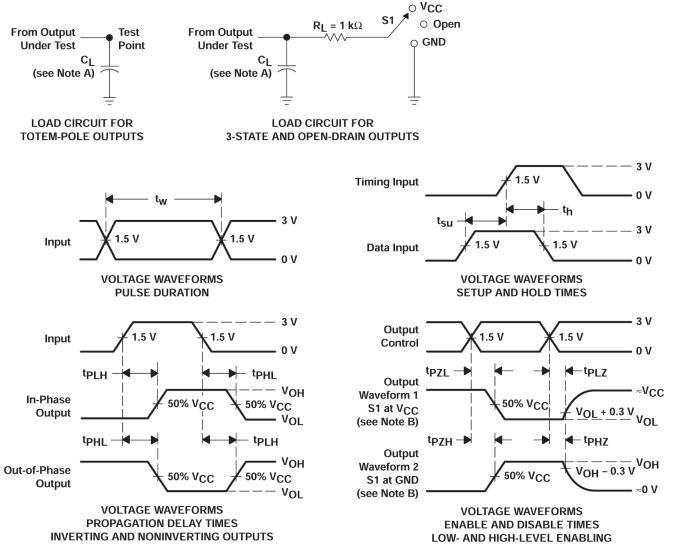
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	No load, f = 1 MHz	12	pF

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7 Parameter Measurement Information



- C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f \leq 3$ ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 7-1. Load Circuit and Voltage Waveforms

TEST	S1		
t _{PLH} /t _{PHL}	Open		
t _{PLZ} /t _{PZL}	V _{CC}		
t _{PHZ} /t _{PZH}	GND		
Open Drain	V _{CC}		

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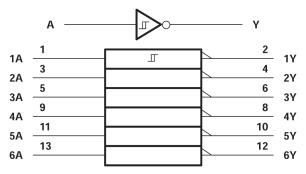


8 Detailed Description

8.1 Overview

Each circuit functions as an independent inverter, but because of the Schmitt action, the inverters have different input threshold levels for positive-going (V_{T+}) and for negative-going (V_{T-}) signals.

8.2 Functional Block Diagram



The † symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Figure 8-1. Logic Diagram, Each Inverter (Positive Logic)

8.3 Device Functional Modes

Table 8-1. Function Table (Each Inverter)

INPUT	OUTPUT
A	Y
Н	L
L	Н

9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Typical Application

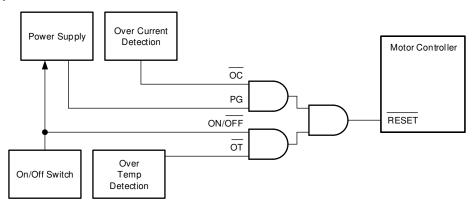


Figure 9-1. Typical Application Block Diagram

9.2 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in the following layout example.

9.3 Layout

9.3.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused (for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used). Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC}, whichever makes more sense for the logic function or is more convenient.

Product Folder Links: SN74AHCT14Q-Q1

9.3.2 Layout Example

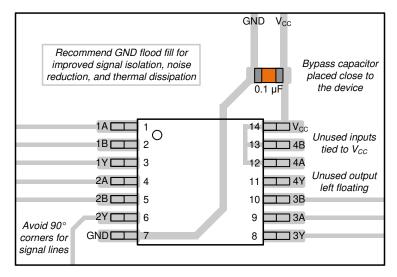


Figure 9-2. Example Layout for the SN74AHCT14Q-Q1

10 Device and Documentation Support

10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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10.3 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

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10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking
	(1)	(2)			(3)	(4)	(5)		(6)
SN74AHCT14QDRG4Q1	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT14Q
SN74AHCT14QDRG4Q1.A	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT14Q
SN74AHCT14QDRQ1	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT14Q
SN74AHCT14QDRQ1.A	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT14Q
SN74AHCT14QPWRG4Q1	Active	Production	TSSOP (PW) 14	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB14Q
SN74AHCT14QPWRG4Q1.A	Active	Production	TSSOP (PW) 14	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB14Q
SN74AHCT14QPWRQ1	Active	Production	TSSOP (PW) 14	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB14Q
SN74AHCT14QPWRQ1.A	Active	Production	TSSOP (PW) 14	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB14Q
SN74AHCT14QWBQARQ1	Active	Production	WQFN (BQA) 14	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHT14Q
SN74AHCT14QWBQARQ1.A	Active	Production	WQFN (BQA) 14	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHT14Q

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



PACKAGE OPTION ADDENDUM

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and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

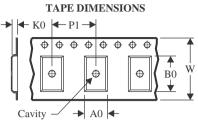
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AHCT14QPWRG4Q1	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHCT14QPWRQ1	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHCT14QPWRQ1	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74AHCT14QWBQARQ1	WQFN	BQA	14	3000	180.0	12.4	2.8	3.3	1.1	4.0	12.0	Q1



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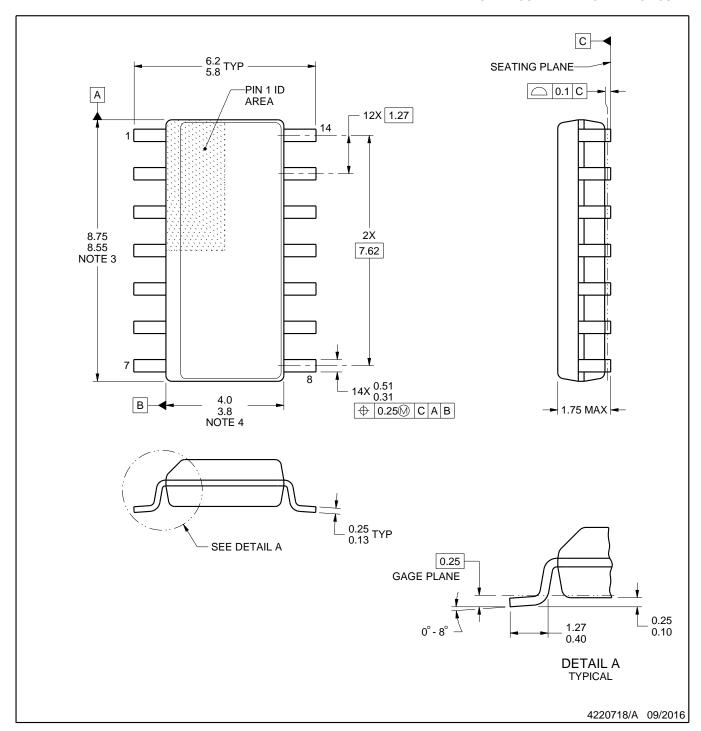


*All dimensions are nominal

7 til dillionolorio di o mominar							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AHCT14QPWRG4Q1	TSSOP	PW	14	2000	353.0	353.0	32.0
SN74AHCT14QPWRQ1	TSSOP	PW	14	2000	353.0	353.0	32.0
SN74AHCT14QPWRQ1	TSSOP	PW	14	2000	353.0	353.0	32.0
SN74AHCT14QWBQARQ1	WQFN	BQA	14	3000	210.0	185.0	35.0



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

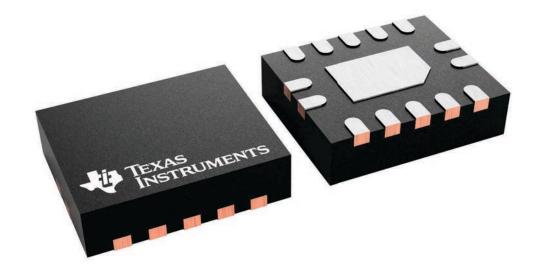
- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



2.5 x 3, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

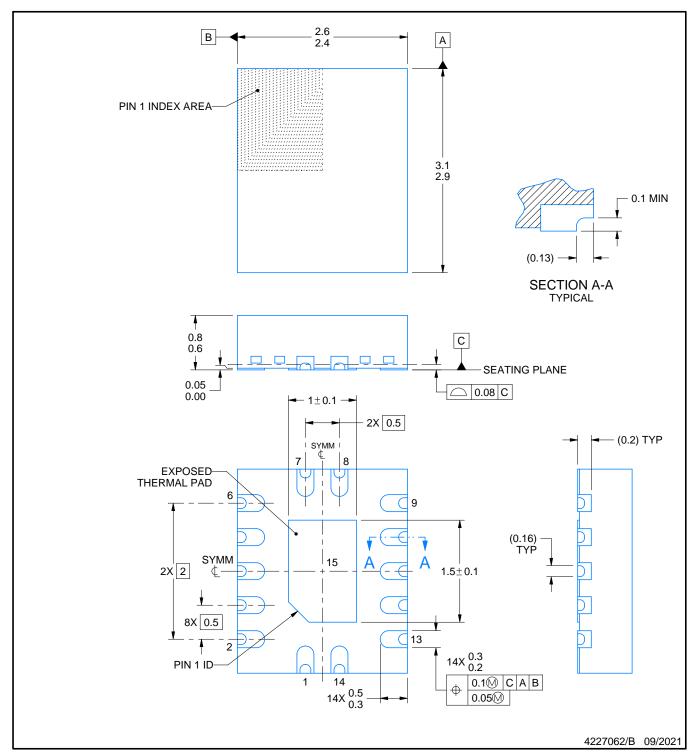
This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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PLASTIC QUAD FLATPACK - NO LEAD

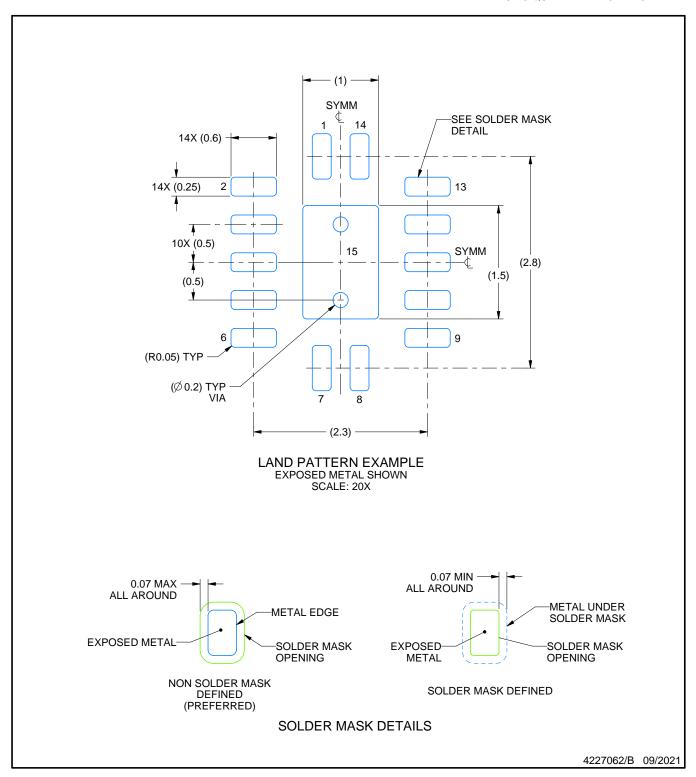


NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

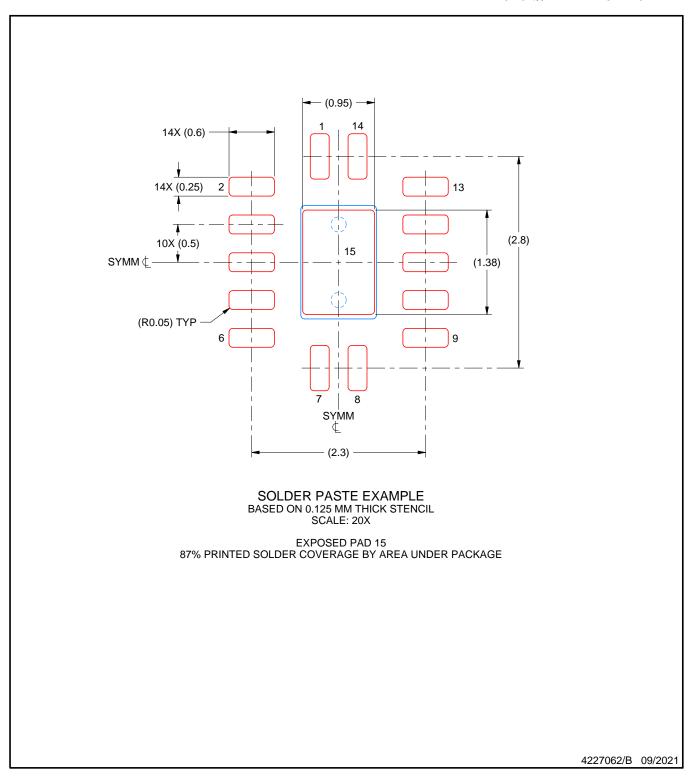


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

^{6.} Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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